Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/665,204	WANG ET AL.
Examiner	Art Unit
Δ Sefer	2826

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPAT, US-PG-Pub, Derwent, EPO & JPO)	. 5/7/2006	AS
257/53,101-103,431-432 (text search)	5/7/2006	AS
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